

## Supplementary Information

# Static and Dynamic Scavenging of Ammoniated Electrons by Nitromethane

Nicolás Rivas,<sup>[a]</sup> Germán Sciaini,<sup>[a]</sup> and Ernesto Marceca<sup>\*[b]</sup>

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<sup>a</sup> *The Ultrafast Electron Imaging Lab, Department of Chemistry and Waterloo Institute for Nanotechnology, University of Waterloo, 200 University Avenue West, Waterloo, Ontario N2L 3G1, Canada.*

<sup>b</sup> *Department of Inorganic, Analytical and Physical Chemistry-FCEN, Universidad de Buenos Aires and INQUIMAE-CONICET. Cdad. Universitaria, Pab. II, Buenos Aires C1428EGA, Argentina. E-mail: [marceca@qi.fcen.uba.ar](mailto:marceca@qi.fcen.uba.ar)*

\* Corresponding author.

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## ARTICLE

## Diagram of the high-pressure optical cell

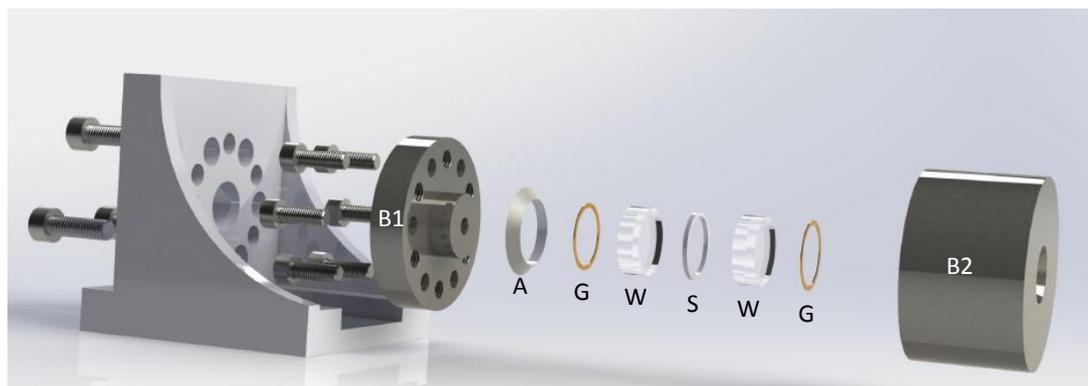


Figure S1. High-pressure optical cell: B1, cell cap; B2 cell body (magnetic stirrer housing graved inside, not shown); G, gold seals; W, sapphire windows; S, spacer (radial holes allow fluid access); A, centring piece.

## Diagram of the fluid handling equipment

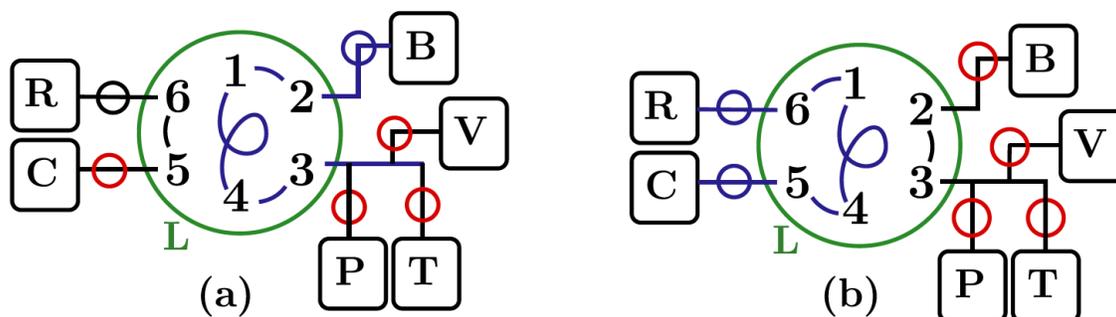


Figure S2. High-pressure ancillary fluid handling equipment: (a) load, (b) injection. L, six-port low-dead-volume valve with a 10  $\mu\text{L}$  sampling loop; C, high-pressure optical cell; R, 3  $\text{cm}^3$  stainless steel auxiliary reservoir; B, stainless steel bottle with the nitromethane-ammonia mother solution; V, access port to the vacuum line; P, purge; T, access to high-pressure syringe pump filled with liquid ammonia and pressure transducer. Needle valves are represented by circles (in blue, open; in red, closed).

### Electron distribution along the pathlength of the cell

The transient electron concentration decreases along the position  $x$  of the optical path following the intensity drop of the UV light. For a given delay  $\tau$ , the transient electron concentration is:  $c_{\text{el}}(x, \tau) = c_{\text{el}}(x = 0, \tau) I(x)/I_0$ , where  $I(x) = I_0 \times 10^{-\epsilon_{\text{CTTS}} c_{\text{KI}} x}$ , being  $\epsilon_{\text{CTTS}}$  the molar extinction coefficient of the iodide's first CTTS band in liquid ammonia, and  $c_{\text{KI}}$  the KI concentration. We used for  $\epsilon_{\text{CTTS}}$  the value  $1.11 \times 10^4 \text{ M}^{-1} \cdot \text{cm}^{-1}$ , which we determined carefully in a former stationary experiment.<sup>1</sup> Finally, the transient electron concentration profile can be related with the measured solution transient absorbance by the expression:  $\Delta A(\tau) = \epsilon_{\text{el}} \int c_{\text{el}}(x, \tau) dx$ ,  $x: 0 \rightarrow b$ , where  $\epsilon_{\text{el}}$  represents the molar extinction of the solvated electron in liquid ammonia. We used for  $\epsilon_{\text{el}}$  the value  $4.5 \times 10^4 \text{ M}^{-1} \cdot \text{cm}^{-1}$ , which was measured by Quinn and Lagowski<sup>2</sup> on ammoniated electrons produced by electrologically-generated K-NH<sub>3</sub> solutions, at a wavelength of 1443 nm, and in presence of KI 0.1M.

In our experimental conditions, transient electron concentrations at the position of the front window were in the range of 2-5 mM, decreasing rapidly into the  $\mu\text{M}$  range when  $x$  is  $\sim 30 \mu\text{m}$ . The mean electron concentration,  $\overline{c_{\text{el}}}(\tau) = 1/b \int c_{\text{el}}(x, \tau) dx$ ,  $x: 0 \rightarrow b$ , can be related with the measured transient absorbance as:  $\Delta A(\tau) = \overline{c_{\text{el}}}(\tau) \epsilon_{\text{el}} b$ .

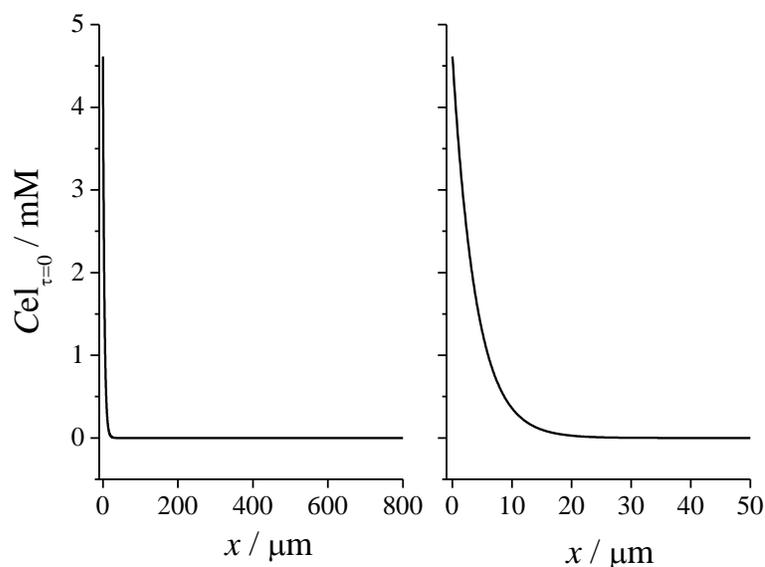


Figure S3. Concentration of electrons along the optical cell's pathlength,  $x$ .

**References**

- 1 R. Fera, G. Sciaini, E. Marceca and R. Fernández-Prini, *Phys. Chem. Chem. Phys.*, 2006, **8**, 4839–4848.
- 2 R. K. Quinn and J. J. Lagowski, *J. Phys. Chem.*, 1969, **73**, 2326–2329.